## DESCRIPTION

These Signetics 2500 Series dual 100-bit Dynamic Shift Registers consist of enhancement mode p-channel MOS devices integrated on a single monolithic chip. They use 2 clock phases.

## FEATURES

- 2506: Bare drain
- 2507: 7.5K Pull down
- 2517: 20K Pull down


## ABSOLUTE MAXIMUM RATINGS1

|  | PARAMETER | RATING | UNIT |
| :---: | :---: | :---: | :---: |
|  | Temperature range |  | ${ }^{\circ} \mathrm{C}$ |
| TA | Operating | 0 to 70 |  |
| Tstg | Storage | -65 to 150 |  |
| PD | Power dissipation at $\mathrm{T}_{\mathrm{A}}=70^{\circ} \mathrm{C} 2$ |  | mW |
|  | T package | 535 |  |
|  | $N$ package | 455 |  |
|  | Clock input voltages | 0.3 to -20 | v |
|  | with respect to $\mathrm{VCC}^{3}$ |  |  |
|  | Supply and data input voltages with respect to $\mathrm{Vcc}^{3}$ | 0.3 to -12 | V |

BLOCK DIAGRAM


PIN CONFIGURATIONS


N PACKAGE


DC ELECTRICAL CHARACTERISTICS $\quad T_{A}=0^{\circ} \mathrm{C}$ to $70^{\circ} \mathrm{C}, \mathrm{V}_{\mathrm{DD}}=-5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{C C}=5 \mathrm{~V} 4$, unless otherwise specified. $5,6,7,8$

| PARAMETER |  | TEST CONDITIONS | LIMITS |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min | Typ | Max |  |
| VIL <br> $V_{\text {IH }}$ <br> VILC <br> VIHC | Input voltage ${ }^{9}$ Low High Clock low Clock high |  |  | $\begin{gathered} -5 \\ 3.2 \\ -12 \\ 4 \end{gathered}$ |  | $\begin{gathered} 1.05 \\ 5.3 \\ -10 \\ 5.3 \end{gathered}$ | V |
| $\begin{aligned} & \mathrm{VOH}_{1} \\ & \mathrm{VOH}_{2} \end{aligned}$ | Output voltage ${ }^{9}$ High (driving MOS) High (driving TTL) | $\mathrm{R}_{\text {INT }}=7.5 \mathrm{k}$ typ, $\mathrm{C}_{\mathrm{L}}=10 \mathrm{pF}, 2507$ only RINT $=20 \mathrm{k}$ typ, 2517 only $R_{L}=3.3 k, V_{D D}=-5 V, 2506$ only | $\begin{aligned} & 3.4 \\ & 3.0 \end{aligned}$ | $\begin{aligned} & 4.0 \\ & 3.5 \end{aligned}$ |  | V |
| ILI | Load current Input 1 | $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$ <br> OUT $1, \phi 1, \phi 2$ and $V_{C C}=5 \mathrm{~V}$, <br> $\operatorname{IN} 2$, OUT 2 and $\operatorname{IN} 1=-5.5 \mathrm{~V}, \mathrm{~V}_{\mathrm{DD}}=-4.5 \mathrm{~V}$ |  | 10 | 500 | nA |
|  | Input 2 | OUT 2, $\phi 1, \phi 2$ and $\mathrm{V}_{\mathrm{CC}}=5 \mathrm{~V}$, <br> $\operatorname{IN} 1$, OUT 1 and $\operatorname{IN} 2=-5.5 \mathrm{~V}, V_{D D}=-4.5 \mathrm{~V}$ |  | 10 | 500 |  |
| ILO | Leakage current ${ }^{10}$ Out 1 | $T_{A}=25^{\circ} \mathrm{C}$ <br> IN $1, \mathrm{Vcc}$, OUT 2 and $\phi 2=5 \mathrm{~V}$, <br> IN $2, V_{D D}$ and OUT $1=-5.5 \mathrm{~V}, \phi 1=-5 \mathrm{~V}$ |  | 10 | 1000 | nA |
|  | Out 2 | IN 1, OUT 1, VCC and $\phi 2=5 \mathrm{~V}$, <br> $\operatorname{IN} 2, \mathrm{VDD}$ and OUT $2=-5.5 \mathrm{~V}, \phi=-5 \mathrm{~V}$ |  | 10 | 1000 |  |
| ILC | Clock leakage current $\begin{aligned} & \phi 1 \\ & \phi 2 \\ & \hline \end{aligned}$ | $\begin{gathered} T_{A}=25^{\circ} \mathrm{C}, \mathrm{~V}_{D D}=-4.5 \mathrm{~V}, \mathrm{All} \text { other pins } 5 \mathrm{~V} \\ V_{\phi 1}=-12 \mathrm{~V} \\ \mathrm{~V}_{\phi 2}=-12 \mathrm{~V} \end{gathered}$ |  | $\begin{aligned} & 10 \\ & 10 \end{aligned}$ | $\begin{aligned} & 1000 \\ & 1000 \end{aligned}$ | nA |
| IDD | VoD supply current | Outputs at logic low or high $3 \mathrm{MHz}, \phi_{1}=150 \mathrm{~ns}, \phi_{2}=100 \mathrm{~ns}$ |  | 12 | 26 | mA |
| $\begin{aligned} & \mathrm{C}_{1 N} \\ & \mathrm{C}_{\phi} \end{aligned}$ | Capacitance Input (1 and 2) Clock input ( $\phi 1, \phi 2$ ) | $\begin{gathered} 1 \mathrm{MHz}, 25 \mathrm{mV} \mathrm{p}-\mathrm{p} \\ \mathrm{~V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{cc}} \\ \mathrm{~V}_{\phi}=\mathrm{V}_{\mathrm{cc}} \end{gathered}$ |  | $\begin{aligned} & 2.5 \\ & 25 \end{aligned}$ | $\begin{gathered} 5 \\ 40 \end{gathered}$ | pF |

AC ELECTRICAL CHARACTERISTICS $T_{A}=25^{\circ} \mathrm{C}, \mathrm{V}_{D D}=-5 \mathrm{~V} \pm 5 \%, \mathrm{~V}_{C C}=5 \mathrm{~V} 4, \mathrm{~V}_{\text {ILC }}=-11 \mathrm{~V}$

| PARAMETER |  | TO | FROM | TEST CONDITIONS | LIMITS |  |  | UNIT |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | Min |  |  | Typ | Max |  |
| Freq. | Clock rep rate |  |  |  |  | . 0006 | 4 | 3 | MHz |
| $\phi 1$ PW <br> $\phi 2$ PW | Pulse width Clock ${ }^{1} 1$ Clock $\$ 2$ |  |  | At 3 MHz | $\begin{aligned} & 150 \\ & 100 \\ & \hline \end{aligned}$ |  |  | ns |
| $\phi_{d}$ $t_{\text {p, }} \mathrm{t}_{\mathrm{F}}$ <br> tw <br> too <br> $t_{A+}$ | Clock pulse delay <br> Clock pulse transition <br> Setup time <br> Data in overlap <br> Delay time | $\phi 2$ <br> Data out | Data in $\phi 1$ | At 3 MHz <br> At 3 MHz $\begin{gathered} t_{\text {RO2 }}=t_{\text {R } 01}=10 \mathrm{~ns} \\ \mathrm{~V}_{\phi}=\mathrm{V}_{\mathrm{CC}}-16 \mathrm{~V}, \text { Data out }=2.5 \mathrm{~V} \end{gathered}$ | $\begin{aligned} & 10 \\ & 10 \\ & 75 \\ & 10 \end{aligned}$ | 90 | $\begin{aligned} & 1000 \\ & 150 \\ & \hline \end{aligned}$ | ns ns ns ns ns |

notes

1. Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or at any other condition above those indicated in the operational sections of this specification is not implied.
2. For operating at elevated temperatures the device must be derated based on a $+150^{\circ} \mathrm{C}$ maximum junction temperature and a thermal resistance of $150^{\circ} \mathrm{C} / \mathrm{W}$ (T package) or $175^{\circ} \mathrm{C} / \mathrm{W}$ (V package).
3. All inputs are protected against static charge.
4. $\mathrm{V}_{\text {cc }}$ tolerance is $\pm 5 \%$. Any variation in actual $\mathrm{V}_{\mathrm{CC}}$ will be tracked directly by $\mathrm{V}_{\mathrm{IL}}$. $\mathrm{V}_{\text {IH }}$ and $\mathrm{V}_{\text {OH }}$ which are stated for a Vcc of exactly 5 volts.
5. Parameters are valid over operating temperature range unless otherwise specified.
6. All voltage meuurements are referenced to ground.
7. Manufacturer reserves the right to make design and process changes and improvements.
8. Typical values are at $+25^{\circ} \mathrm{C}$ and typical supply voltages.
9. Logic Convention: Data Lines - Positive; Clocks -Negative.
10. $\mathrm{V}_{\mathrm{OL}}$ (for this bare drain device) is a function only of the driven gate characteristics together with the external pull-down resistor. (RpD).

## TIMING DIAGRAM



